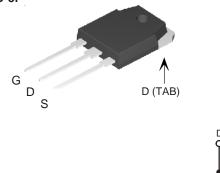


N-Channel 650V(D-S) Super Junction Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V) at T _J max.	650					
R _{DS(on)} at 25 °C (Ω)	$V_{GS} = 10 V$	0.06				
Q _g max. (nC)	273					
Q _{gs} (nC)	46					
Q _{gd} (nC)	79					
Configuration	Single					





FEATURES

- + Low figure-of-merit (FOM) $R_{\text{on}} \mathrel{x} Q_{\text{g}}$
- Low input capacitance (C_{iss})
- Reduced switching and conduction losses
- Ultra low gate charge (Q_g)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial
 - Welding
 - Induction heating
 - Motor drives
 - Battery chargers
 - Renewable energy
 - Solar (PV inverters)

ABSOLUTE MAXIMUM RATINGS ($T_C = 25 \text{ °C}$, unless otherwise noted)									
PARAMETER			SYMBOL	LIMIT	UNIT				
Drain-Source Voltage			V _{DS}	650	V				
Gate-Source Voltage			V _{GS}	± 30	V				
Continuous Drain Current ($T_J = 150 \ ^{\circ}C$)	V _{GS} at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	۱ _D	47					
	V _{GS} at 10 V	T _C = 100 °C		30	А				
Pulsed Drain Current ^a			I _{DM}	142					
Linear Derating Factor				3.3	W/°C				
Single Pulse Avalanche Energy ^b			E _{AS}	1410	mJ				
Maximum Power Dissipation			PD	415	W				
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C				
Drain-Source Voltage Slope	T _J = 125 °C		d\//dt	37	1//20				
Reverse Diode dV/dt ^d			dV/dt	9	V/ns				
Soldering Recommendations (Peak Temperature) ^c	for 10 s			300	°C				

S N-Channel MOSFET

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 10 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





THERMAL RESISTANCE RATI	NGS								
PARAMETER	SYMBOL	TYP.	TYP. MAX.			UNIT			
Maximum Junction-to-Ambient	R _{thJA}	- 40			*OAV				
Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.3				°C/W			
SPECIFICATIONS (T _J = 25 °C, u	nless otherwi	se noted)							
PABAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT		
Static									
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D =	250 µA	650	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$		$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ Reference to 25 °C, $I_D = 1 \text{ mA}$			0.70	-	V/°C	
Gate-Source Threshold Voltage (N)	V _{GS(th)}		= V _{GS} , I _D =	-	2	-	4	V	
	GO(III)	$V_{GS} = \pm 20 V$		-	-	± 100	nA		
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 30 \text{ V}$			-	-	± 1	μA	
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 650 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	1		
		$V_{DS} = 520 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$			-	-	25	μA	
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$ $I_D = 24 A$		-	0.06	-	Ω		
Forward Transconductance	9 _{fs}	V _{DS} = 30 V, I _D = 24 A		-	16.7	-	S		
Dynamic		•			•	•	•		
Input Capacitance	C _{iss}		V _{GS} = 0 V,		-	5682	-		
Output Capacitance	C _{oss}	$V_{DS} = 100 V,$ f = 1 MHz		-	251	-	pF		
Reverse Transfer Capacitance	C _{rss}			-	1	-			
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V_{DS} = 0 V to 520 V, V_{GS} = 0 V		-	192	-			
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	665	-			
Total Gate Charge	Qg				-	182	273		
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 24 \text{ A}, V_{DS} = 520 \text{ V}$		-	46	-	nC		
Gate-Drain Charge	Q _{gd}				-	79	-		
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 520 \text{ V}, \text{ I}_{D} = 6 \text{ A},$ $V_{GS} = 10 \text{ V}, \text{ R}_{g} = 9.1 \Omega$		-	47	94	- ns		
Rise Time	t _r			-	87	131			
Turn-Off Delay Time	t _{d(off)}			-	156	234			
Fall Time	t _f			-	103	206			
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.64	-	Ω		
Drain-Source Body Diode Characteristic	s								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	47	- A		
Pulsed Diode Forward Current	I _{SM}			-	-	139			
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 24 A, V _{GS} = 0 V		-	0.9	1.2	V		
Reverse Recovery Time	t _{rr}		- U		-	753	1506	ns	
Reverse Recovery Charge	Q _{rr}		$T_J = 25 \ ^{\circ}C, I_F = I_S = 24 \ A,$		-	14	28	μC	
Reverse Recovery Current	I _{RRM}	dl/dt = 100 A/µs, V _R = 25 V		-	28	-	A		

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPCIAL CHARACTERISTICS (25 °C, unless otherwise noted)

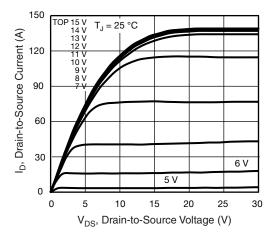


Fig. 1 - Typical Output Characteristics

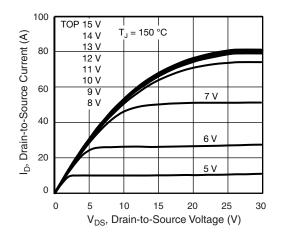


Fig. 2 - Typical Output Characteristics

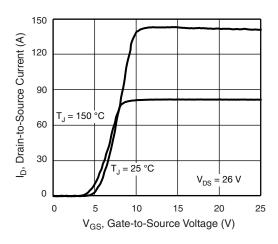


Fig. 3 - Typical Transfer Characteristics

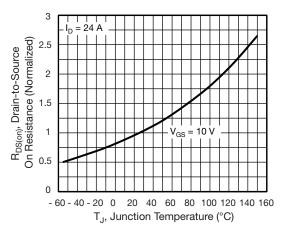


Fig. 4 - Normalized On-Resistance vs. Temperature

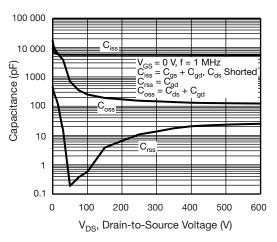


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

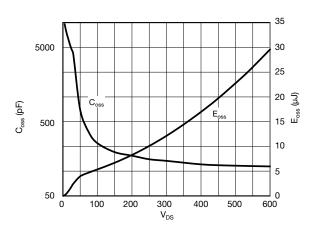


Fig. 6 - Coss and Eoss vs. VDS

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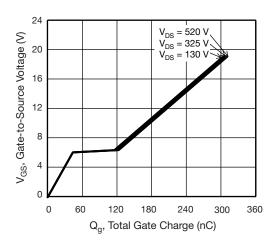


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

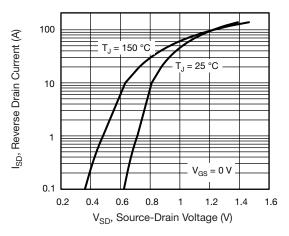


Fig. 8 - Typical Source-Drain Diode Forward Voltage

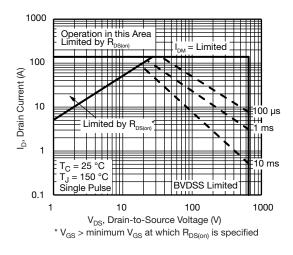


Fig. 9 - Maximum Safe Operating Area

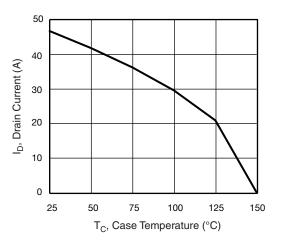


Fig. 10 - Maximum Drain Current vs. Case Temperature

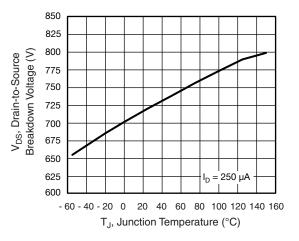
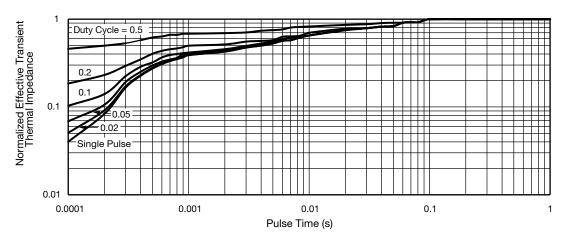


Fig. 11 - Temperature vs. Drain-to-Source Voltage



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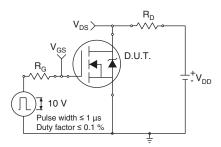


Fig. 13 - Switching Time Test Circuit

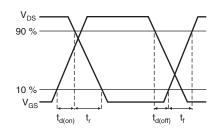


Fig. 14 - Switching Time Waveforms

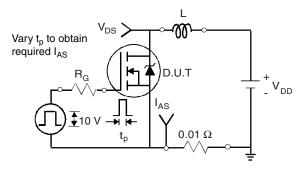


Fig. 15 - Unclamped Inductive Test Circuit

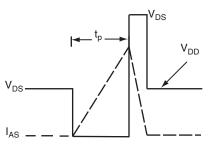


Fig. 16 - Unclamped Inductive Waveforms

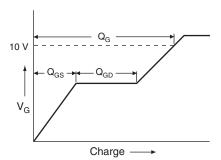


Fig. 17 - Basic Gate Charge Waveform

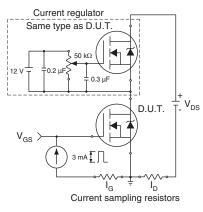


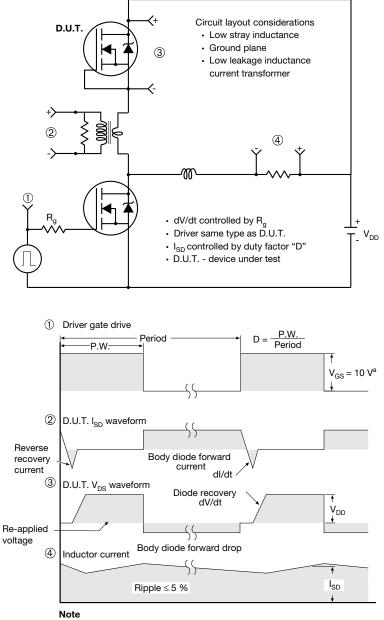
Fig. 18 - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit

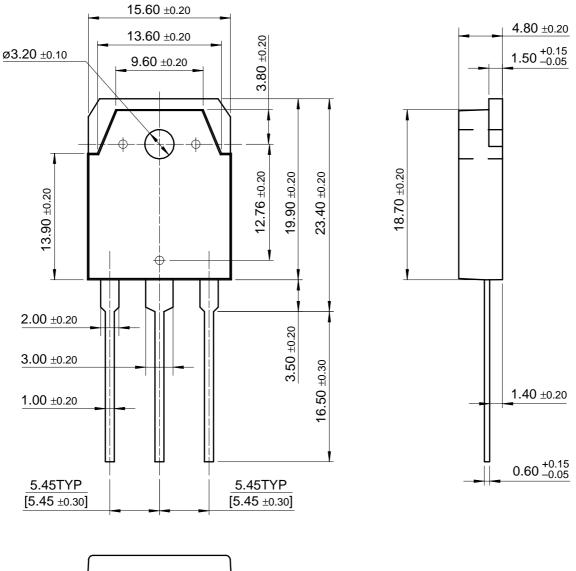


a. $V_{GS} = 5 V$ for logic level devices

Fig. 19 - For N-Channel



TO-3P







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